

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination LUNDELL ET AL.	
		Examiner Aamir Haq	Art Unit 2642	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,254,249	07-2001	Kim et al.	362/109
*	B	US-2002/0177467	11-2002	Hsu, Chien Kuo	455/556
*	C	US-6,336,727	01-2002	Kim, Moon J.	362/23
*	D	US-2003/0107554	06-2003	Motegi, Seiko	345/168
*	E	US-2003/0099116	05-2003	Nousiainen, Jaakko	362/559
*	F	US-5,815,225	09-1998	Nelson, Richard F.	349/65
*	G	US-5,684,516	11-1997	Cseledy et al.	347/8
*	H	US-6,726,106	04-2004	Han et al.	235/472.01
*	I	US-5,237,607	08-1993	Diamantis, Perry W.	379/419
*	J	US-2004/0085745	05-2004	Yoshihara, Shigeo	362/008
*	K	US-2003/0100332	05-2003	Engstrom et al.	455/550
*	L	US-5,901,206	05-1999	Soon, Min Tet	379/110.01
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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